

Fig. 1 shows that the various coordinates in (15) can be replaced as follows:

$$\begin{aligned} Y_1 &= r_{12} \sin \varphi_1 & Z_1 &= r_{12} \cos \varphi_1 \\ Z_3 &= r_{23} & Z_4 &= r_{23} - r_{34} \cos \varphi_2 \\ (X_4^2 + Y_4^2)^{1/2} &= r_{34} \sin \varphi_2, \end{aligned}$$

where  $r_{mn}$  is the distance between atoms  $m$  and  $n$ . Equation (15) for the variance of the torsion angle,  $\tau$ , then becomes:

$$\begin{aligned} \sigma^2(\tau) &= \frac{\sigma_1^2}{r_{12}^2 \sin^2 \varphi_1} + \frac{\sigma_2^2}{r_{23}^2} \left[ \left( \frac{r_{23} - r_{12} \cos \varphi_1}{r_{12} \sin \varphi_1} \right)^2 \right. \\ &\quad \left. - 2 \left( \frac{r_{23} - r_{12} \cos \varphi_1}{r_{12} \sin \varphi_1} \right) \cot \varphi_2 \cos \tau + \cot^2 \varphi_2 \right] \\ &\quad + \frac{\sigma_3^2}{r_{23}^2} \left[ \cot^2 \varphi_1 - 2 \left( \frac{r_{23} - r_{34} \cos \varphi_2}{r_{34} \sin \varphi_2} \right) \cot \varphi_1 \cos \tau \right. \\ &\quad \left. + \left( \frac{r_{23} - r_{34} \cos \varphi_2}{r_{34} \sin \varphi_2} \right)^2 \right] + \frac{\sigma_4^2}{r_{34}^2 \sin^2 \varphi_2}. \quad (16) \end{aligned}$$

Use of the special coordinates in (8') leads to the torsion angle:

$$|\tau| = \cos^{-1} \frac{Y_4}{(X_4^2 + Y_4^2)^{1/2}}. \quad (17)$$

The convention of the 'right-hand rule' (Klyne & Prelog, 1960) is used to fix the sign of  $\tau$ . In order to determine the

sign, in a right-handed system with  $Y_1 > 0$  and  $Z_3 > 0$ , it is necessary only to examine  $X_4$ . The sign of  $\tau$  is the sign of  $-X_4$ .

For the purpose of programming a computer to calculate the standard deviation of the torsion angle, equation (15) seems most appropriate. If, however, the six structural parameters are known, then equation (16) would be more suitable.

The function-and-error program of Busing & Levy (1961) included a provision for calculating the dihedral angle and its standard error for two planes each defined by three atoms. The torsion-angle calculation is a special case in which two atoms are common to both planes. In this program the standard error is calculated from the full covariance matrix, and the necessary derivatives are evaluated by numerical differentiation.

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**Normal probability plot analysis of small samples.\*** By WALTER C. HAMILTON, *Chemistry Department, Brookhaven National Laboratory, Upton, New York, U.S.A.* and S. C. ABRAHAMS, *Bell Telephone Laboratories, Incorporated, Murray Hill, New Jersey, U.S.A.*

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In using normal probability plots for comparing two sets of crystallographic data [Abrahams, S. C. & Keve, E. T. (1971), *Acta Cryst.* **A27**, 157] note should be taken of the fact that the expected values of normal order statistics are not given exactly by the percentage points of the normal distribution. This becomes an important consideration only for small samples. Tables of expected ranked exact moduli of normal observations, for sample sizes to 41, are presented: these are useful for half-normal probability plots.

Differences between independent measurements or calculated values of the same  $i$ th crystallographic quantity,  $\Delta_i = F(1)_i - F(2)_i$ , are readily analyzed by the normal probability plot method (Abrahams & Keve, 1971) in terms of the pooled standard deviation  $\sigma_i = [\sigma^2 F(1)_i + \sigma^2 F(2)_i]^{1/2}$ . A plot of the  $j$  ranked values of the weighted deviations  $\Delta_i/\sigma_i$  (where  $i=1$  refers to the largest  $\Delta_i/\sigma_i$ ) against the expected values  $\xi(i|j)$  should result in a scatter of points about a straight line of unit slope that passes through the origin. If the weighted deviations are drawn from a normal distribution, a reasonable assumption for a crystallographic experiment, then the expected values for large  $j$  are given approximately by the percentage points  $X_i$  of the normal distribution, with

$$P(X_i) = \frac{1}{\sqrt{2\pi}} \int_{-X_i}^{X_i} \exp(-\alpha^2/2) d\alpha = |(j-2i+1)/j| \quad (1)$$

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For small values of  $j$ , especially for  $j < 50$ , the deviations between the values given by equation (1) and the exact values as tabulated by Harter (1961) become appreciable, especially at the extremes of the array. Four examples are given in Table 1. The exact values should always be used for small samples.

If the sign of  $\Delta_i$  is without significance, as in comparison of two sets of position parameters, the half-normal probability plot should be used (Abrahams & Keve, 1971). For large samples, the expected values may again be obtained from the percentage points of the normal distribution, with  $P(X_i) = (2j-2i+1)/2j$ .† For  $j$  small, these approximate values are appreciably in error, and the exact values should be used. The expected value of the  $i$ th largest modulus of

† The expression given for this quantity in Abrahams & Keve (1971) is misprinted as  $(2i+1)/2j$ ; it should have read  $(2i-1)/2j$ , where  $i=1$  refers to the smallest observation. For consistency with the full-normal case notation, we use the expression above, where  $i=1$  refers to the largest observation.

Table 1. *Expected values of normal order statistics*

Approximate values are obtained from percentage points of the normal distribution as proposed by Abrahams & Keve (1971).  
Exact values are from Harter (1961). Note that  $\xi(j+1-i|j) = -\xi(i|j)$ .

$j=5$				$j=50$			
$i$	$P(X_i)$	Approx. $\xi(i j)$	Exact $\xi(i j)$	$i$	$P(X_i)$	Approx. $\xi(i j)$	Exact $\xi(i j)$
1	0.80	1.282	1.163	1	0.98	2.326	2.249
2	0.40	0.524	0.495	2	0.94	1.881	1.855
3	0.00	0.000	0.000	3	0.90	1.645	1.629
				4	0.86	1.476	1.464
				5	0.82	1.341	1.331
				6	0.78	1.226	1.218
				7	0.74	1.126	1.119
				8	0.70	1.037	1.030
				9	0.66	0.954	0.949
				10	0.62	0.878	0.873
				11	0.58	0.806	0.802
				12	0.54	0.739	0.735
				13	0.50	0.674	0.671
				14	0.46	0.613	0.610
				15	0.42	0.553	0.551
				16	0.38	0.496	0.494
				17	0.34	0.440	0.438
				18	0.30	0.385	0.384
				19	0.26	0.332	0.330
				20	0.22	0.279	0.278
				21	0.18	0.228	0.227
				22	0.14	0.176	0.176
				23	0.10	0.126	0.125
				24	0.06	0.075	0.075
				25	0.02	0.025	0.025

  

$j=10$				$j=25$			
$i$	$P(X_i)$	Approx. $\xi(i j)$	Exact $\xi(i j)$	$i$	$P(X_i)$	Approx. $\xi(i j)$	Exact $\xi(i j)$
1	0.90	1.645	1.539	1	0.96	2.054	1.965
2	0.70	1.036	1.001	2	0.88	1.555	1.524
3	0.50	0.675	0.656	3	0.80	1.282	1.263
4	0.30	0.385	0.376	4	0.72	1.080	1.067
5	0.10	0.126	0.123	5	0.64	0.915	0.905
				6	0.56	0.772	0.764
				7	0.48	0.643	0.637
				8	0.40	0.524	0.519
				9	0.32	0.412	0.409
				10	0.24	0.305	0.303
				11	0.16	0.202	0.200
				12	0.08	0.100	0.100

Table 2. *Expected values of half-normal order statistics (ranked moduli of normal observations)*

Approximate values are obtained from percentage points of the normal distribution: exact values have been calculated from equation (2).

$j=5$				$j=25$			
$i$	$P(X_i)$	Approx. $\xi_{1/2}(i j)$	Exact $\xi_{1/2}(i j)$	$i$	$P(X_i)$	Approx. $\xi_{1/2}(i j)$	Exact $\xi_{1/2}(i j)$
1	0.90	1.645	1.570	1	0.98	2.326	2.254
2	0.70	1.036	1.044	2	0.94	1.881	1.860
3	0.50	0.675	0.712	3	0.90	1.645	1.635
4	0.30	0.385	0.448	4	0.86	1.476	1.470
5	0.10	0.126	0.216	5	0.82	1.341	1.338
				6	0.78	1.227	1.226
				7	0.74	1.126	1.128
				8	0.70	1.036	1.039
				9	0.66	0.954	0.958
				10	0.62	0.878	0.883
				11	0.58	0.806	0.813
				12	0.54	0.739	0.746
				13	0.50	0.675	0.683
				14	0.46	0.613	0.622
				15	0.42	0.553	0.564
				16	0.38	0.496	0.507
				17	0.34	0.440	0.452
				18	0.30	0.385	0.399
				19	0.26	0.332	0.347
				20	0.22	0.279	0.295
				21	0.18	0.228	0.245
				22	0.14	0.176	0.195
				23	0.10	0.126	0.146
				24	0.06	0.075	0.097
				25	0.02	0.025	0.048

  

$j=10$			
$i$	$P(X_i)$	Approx. $\xi_{1/2}(i j)$	Exact $\xi_{1/2}(i j)$
1	0.95	1.960	1.881
2	0.85	1.440	1.424
3	0.75	1.150	1.151
4	0.65	0.935	0.944
5	0.55	0.755	0.772
6	0.45	0.598	0.621
7	0.35	0.454	0.483
8	0.25	0.319	0.355
9	0.15	0.189	0.233
10	0.05	0.063	0.115



an observation in a sample of size  $j$  drawn from a normal population with zero mean and unit variance is given exactly by

$$\xi_{1/2}(i|j) = \frac{2j!}{(j-i)!(i-1)!} \times \int_0^\infty \frac{x \exp(-x^2/2)}{\sqrt{2\pi}} (2P-1)^{j-i} (2-2P)^{i-1} dx \quad (2)$$

where

$$P = \frac{1}{\sqrt{2\pi}} \int_{-\infty}^x \exp(-\alpha^2/2) d\alpha.$$

A comparison of exact [equation (2)] and approximate expected magnitudes of the ranked half-normal order statistics, for three values of  $j$ , is given in Table 2. The exact moduli, for values of  $j=2[1] 41$ , for all values of

$i$  (to our knowledge, not previously published) are presented in Table 3. The normal approximation is satisfactory for intermediate values of  $i$  (cf. Table 2), but remains in error by about 2% for values of  $j$  as high as 400. The extreme smallest value has a limiting exact value which is double that for the normal approximation, although the *absolute* difference between exact and approximate values is of no practical importance for large values of  $j$ .

Complete values of the full- and half-normal order statistics will appear in Volume 4 of *International Tables for X-ray Crystallography*.

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**Multiple diffraction effects in neutron single-crystal diffractometry.** By R. COLELLA\*, *Department of Materials Science and Engineering, Bard Hall, Cornell University, Ithaca, N. Y. 14850 U.S.A.*

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The  $n$ -beam dynamical theory of diffraction is applied to multiple neutron diffraction. A computer program has been adapted to the neutron case from one originally developed for high energy electron diffraction in reflection. The integrated intensities are computed for the two and multibeam cases of the 002 reflection and compared with experiment. It is shown that only a negligible fraction of the incident beam satisfies the conditions for multiple diffraction.

The importance of multiple neutron diffraction in the Bragg case was recognized early by Moon & Shull (1961) and subsequently by Borgonovi & Caglioti (1962). The latter authors found remarkable effects in the 002 reflection from mosaic crystals such as nickel, aluminum, and pyrite, whereas they were not able to observe any appreciable effect in relatively perfect crystals such as LiF and NaCl. Since multiple diffraction is essentially related to a dynamical interaction among diffracted beams, the reason for this negative result is not clear, and a theoretical evaluation of these effects seems worthwhile.

The appropriate tool for this interpretation is the  $n$ -beam dynamical theory of diffraction and, for this purpose, a computer program originally developed for high energy electron diffraction in reflection (Colella, 1971; Colella & Menadue, 1971) has been adapted to the neutron case with a few minor modifications.

In Borgonovi & Caglioti's experiment, the crystal was oriented for the 002 Bragg reflection and then rotated around the [002] normal. The intensity was measured as a function of  $\varphi$ , the azimuthal angle. The divergence of the incident beam in the diffraction plane, of the order of several minutes of arc (Caglioti & Ricci, 1962), was much higher than the Darwin width of the crystal. In this situation, the intensity measured by the counter corresponds to the integrated intensity of the diffraction profile for an  $\omega$  scan. For the sake of comparison with Borgonovi & Caglioti's experiment,

the 002 integrated intensity for an  $\omega$  scan (Bragg case) was computed when one or two strong reflections other than 002 were simultaneously excited. In relation to the nickel 002 azimuthal plot obtained by Borgonovi & Caglioti, numerous multibeam rocking curves for LiF and NaCl single crystals were computed in the vicinity of  $\varphi=36-37^\circ$ , where the 002 intensity suffers the most drastic changes.† The results are reported in Table 1. The 002 integrated intensity

† The azimuthal angle  $\varphi=0$  corresponds to a [010] axis lying in the diffraction plane.

Table 1. *The effects of simultaneous reflections on the 002 integrated intensity*

The simultaneous reflections are listed in the second column from the left. When two simultaneous reflections are involved (four-beam case), their  $hkl$  indices are indicated by parentheses. The maximum and minimum percentage changes of the 002 integrated intensity are indicated, along with the angular width on the azimuthal scale.  $I_2$  is the 002 two-beam integrated intensity.

Crystal	$hkl$	$\Delta I/I_2 (\times 100)$	$\Delta\varphi$ (sec)
LiF	$\bar{1}31$	-15 +466	14
	$(042)$ $(040)$	+33 -30	8.3
	$\bar{1}31$	-2.5 +31.4	3.1
NaCl	$\bar{1}31$	-2.5 +31.4	3.1

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